



Attorney Docket: 3319.3A (02US2)

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant:

James W. Overbeck

Serial No:

10/034,620

Filed:

December 27, 2001

For:

WIDE FIELD OF VIEW AND HIGH SPEED SCANNING MICROSCOPY

Examiner: T.Q. Nguyen

Art Unit: 2872

COMMISSIONER FOR PATENTS WASHINGTON, D.C. 20231

Sir:

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RESPONSE

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In response to the Communication mailed April 18, 2003, Applicant re-summits the Response mailed initially on April 2, 2003, now written in the "new" format. The claim changes are written to replace the Response filed on April 2, 2003 as follows: